

Octal inverting buffer with 30Ω series termination resistors (3-State)

74ABT2240

FEATURES

- Octal bus interface
- 3-State buffers
- Live insertion/extraction permitted
- Outputs include series resistance of 30Ω, making external termination resistors unnecessary
- Output capability: +12mA/-32mA
- Latch-up protection exceeds 500mA per Jedecl Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power-up 3-State
- Same part as 74ABT240-1

DESCRIPTION

The 74ABT2240 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed.

The 74ABT2240 device is an octal inverting buffer that is ideal for driving bus lines. The device features two Output Enables ($1\bar{OE}$, $2\bar{OE}$), each controlling four of the 3-State outputs.

The 74ABT2240 is designed with 30Ω series resistance in both the High and Low states of the output. This design reduces line noise in applications such as memory address drivers, clock drivers and bus receivers/transmitters.

The 74ABT2240 is the same as the 74ABT240-1. The part number has been changed to reflect industry standards.

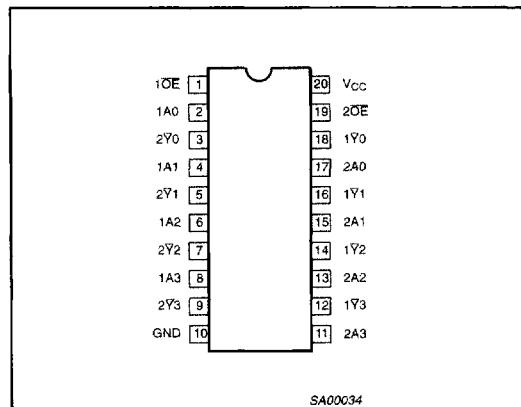
QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^\circ C$; GND = 0V	TYPICAL	UNIT
t_{PLH} t_{PHL}	Propagation delay An to \bar{Y}_n	$C_L = 50\text{pF}$; $V_{CC} = 5\text{V}$	2.8 4.3	ns
C_{IN}	Input capacitance	$V_I = 0\text{V}$ or V_{CC}	3	pF
C_{OUT}	Output capacitance	Outputs disabled; $V_O = 0\text{V}$ or V_{CC}	7	pF
I_{CCZ}	Total supply current	Outputs disabled; $V_{CC} = 5.5\text{V}$	50	μA

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic DIP	-40°C to +85°C	74ABT2240 N	74ABT2240 N	SOT146-1
20-Pin plastic SO	-40°C to +85°C	74ABT2240 D	74ABT2240 D	SOT163-1
20-Pin Plastic SSOP Type II	-40°C to +85°C	74ABT2240 DB	74ABT2240 DB	SOT339-1
20-Pin Plastic TSSOP Type I	-40°C to +85°C	74ABT2240 PW	7ABT2240PW DH	SOT360-1

PIN CONFIGURATION

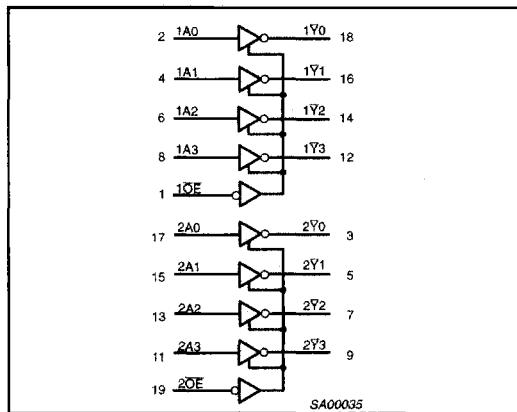
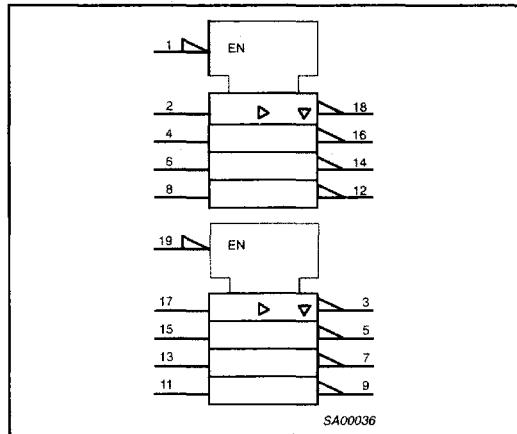


PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
2, 4, 6, 8	1A0 – 1A3	Data inputs
11, 13, 15, 17	2A0 – 2A3	Data inputs
18, 16, 14, 12	1Y0 – 1Y3	Data outputs
9, 7, 5, 3	2Y0 – 2Y3	Data outputs
1, 19	1OE, 2OE	Output enables
10	GND	Ground (0V)
20	V _{CC}	Positive supply voltage

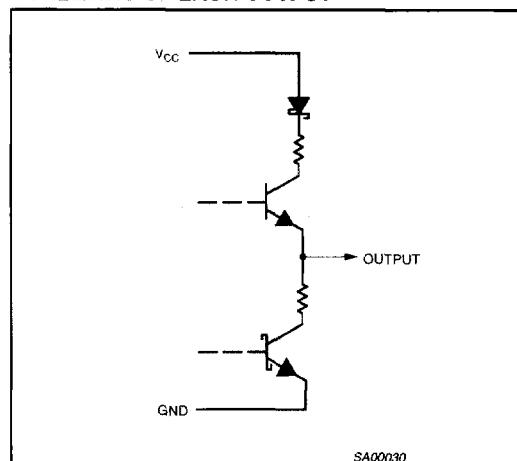
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LOGIC SYMBOL**LOGIC SYMBOL (IEE/IEC)****FUNCTION TABLE**

INPUTS				OUTPUTS	
1OE	1An	2OE	2An	1Yn	2Yn
L	L	L	L	H	H
L	H	L	H	L	L
H	X	H	X	Z	Z

H = High voltage level
L = Low voltage level
X = Don't care
Z = High impedance "off" state

SCHEMATIC OF EACH OUTPUT**ABSOLUTE MAXIMUM RATINGS^{1, 2}**

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V _I < 0	-18	mA
V _I	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	128	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		Min	Max	
V _{CC}	DC supply voltage	4.5	5.5	V
V _I	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level input voltage		0.8	V
I _{OH}	High-level output current		-32	mA
I _{OL}	Low-level output current		12	mA
Δt/ΔV	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS				UNIT	
			T _{amb} = +25°C			T _{amb} = -40°C to +85°C		
			Min	Typ	Max	Min		
V _{IK}	Input clamp voltage	V _{CC} = 4.5V; I _{IK} = -18mA		-0.9	-1.2		-1.2	V
V _{OH}	High-level output voltage	V _{CC} = 4.5V; I _{OH} = -3mA; V _I = V _{IL} or V _{IH}	2.5	2.9		2.5		V
		V _{CC} = 5.0V; I _{OH} = -3mA; V _I = V _{IL} or V _{IH}	3.0	3.4		3.0		V
		V _{CC} = 4.5V; I _{OH} = -32mA; V _I = V _{IL} or V _{IH}	2.0	2.4		2.0		V
V _{OL}	Low-level output voltage	V _{CC} = 4.5V; I _{OL} = 5mA; V _I = V _{IL} or V _{IH}		0.32	0.55		0.55	V
		V _{CC} = 4.5V; I _{OL} = 12mA; V _I = V _{IL} or V _{IH}			0.8		0.8	V
I _I	Input leakage current	V _{CC} = 5.5V; V _I = GND or 5.5V		±0.01	±1.0		±1.0	μA
I _{OFF}	Power-off leakage current	V _{CC} = 0.0V; V _O or V _I ≤ 4.5V		±5.0	±100		±100	μA
I _{PUD}	Power-up/down 3-State output current ³	V _{CC} = 2.1V; V _O = 0.5V; V _I = GND or V _{CC} ; V _{OE} = Don't care		±5.0	±50		±50	μA
I _{OZH}	3-State output High current	V _{CC} = 5.5V; V _O = 2.7V; V _I = V _{IL} or V _{IH}		0.01	50		50	μA
I _{OZL}	3-State output Low current	V _{CC} = 5.5V; V _O = 0.5V; V _I = V _{IL} or V _{IH}		-0.01	-50		-50	μA
I _{CEX}	Output high leakage current	V _{CC} = 5.5V; V _O = 5.5V; V _I = GND or V _{CC}		5.0	50		50	μA
I _O	Output current ¹	V _{CC} = 5.5V; V _O = 2.5V	-50	-100	-180	-50	-180	mA
I _{CCH}	Quiescent supply current	V _{CC} = 5.5V; Outputs High, V _I = GND or V _{CC}		50	250		250	μA
I _{CCL}		V _{CC} = 5.5V; Outputs Low, V _I = GND or V _{CC}		24	30		30	mA
I _{CCZ}		V _{CC} = 5.5V; Outputs 3-State; V _I = GND or V _{CC}		50	250		250	μA
ΔI _{CC}	Additional supply current per input pin ²	Outputs enabled, one data input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = 5.5V		0.5	1.5		1.5	mA
		Outputs 3-State, one data input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = 5.5V		50	250		250	μA
		Outputs 3-State, one enable input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = 5.5V		0.5	1.5		1.5	mA

NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- This is the increase in supply current for each input at 3.4V.
- This parameter is valid for any V_{CC} between 0V and 2.1V, with a transition time of up to 10msec. From V_{CC} = 2.1V to V_{CC} = 5V ± 10% a transition time of up to 100μsec is permitted.

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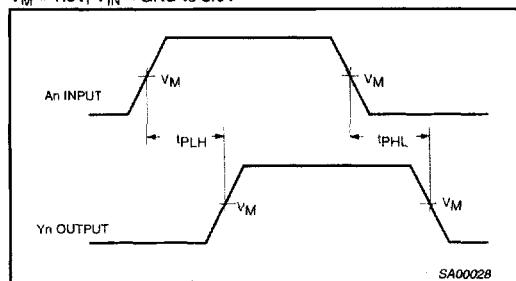
AC CHARACTERISTICS

$V_{DD} = 0V$; $t_P = t_F = 2.5ns$; $C_L = 50pF$, $R_L = 500\Omega$

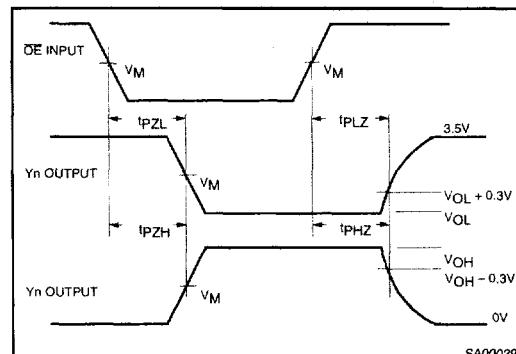
SYMBOL	PARAMETER	WAVEFORM	LIMITS					UNIT	
			$T_{amb} = +25^\circ C$ $V_{CC} = +5.0V$			$T_{amb} = -40^\circ C \text{ to } +85^\circ C$ $V_{CC} = +5.0V \pm 0.5V$			
			Min	Typ	Max	Min	Max		
t_{PLH}	Propagation delay An to \bar{Y}_n	1	1.0 3.0	2.8 4.3	4.0 5.8	1.0 3.0	4.9 6.0	ns	
t_{PHL}	Output enable time to High and Low level	2	1.5 4.2	3.4 5.5	4.7 7.6	1.5 4.2	5.8 8.4	ns	
t_{PZH}	Output disable time from High and Low level	2	1.9 2.5	4.1 3.4	5.0 5.8	1.9 2.5	5.6 6.4	ns	

AC WAVEFORMS

$V_M = 1.5V$, $V_{IN} = GND$ to $3.0V$



Waveform 1. Waveforms Showing the Input (An) to Output (\bar{Y}_n) Propagation Delays



Waveform 2. Waveforms Showing the 3-State Output Enable and Disable Times

TEST CIRCUIT AND WAVEFORMS

